SN54ABT16245A, SN74ABT16245A 16-BIT BUS TRANSCEIVERS WITH 3-STATE OUTPUTS

SCBS300E - MARCH 1994 - REVISED MARCH 1999

- Members of the Texas Instruments Widebus™ Family
- State-of-the-Art EPIC-IIB™ BiCMOS Design Significantly Reduces Power Dissipation
- Typical V_{OLP} (Output Ground Bounce) < 1 V at V_{CC} = 5 V, T_A = 25°C
- High-Impedance State During Power Up and Power Down
- Distributed V_{CC} and GND Pin Configuration Minimizes High-Speed Switching Noise
- Flow-Through Architecture Optimizes PCB Layout
- High-Drive Outputs (–32-mA I_{OH}, 64-mA I_{OL})
- Latch-Up Performance Exceeds 500 mA Per JESD 17
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Package Options Include Plastic Thin Very Small-Outline (DGV), Shrink Small-Outline (DL), and Thin Shrink Small-Outline (DGG) Packages and 380-mil Fine-Pitch Ceramic (WD) Flat Package Using 25-mil Center-to-Center Spacings

description

The 'ABT16245A devices are 16-bit noninverting 3-state transceivers designed for synchronous two-way communication between data buses. The control-function implementation minimizes external timing requirements.

SN54ABT16245A . . . WD PACKAGE SN74ABT16245A . . . DGG, DGV, OR DL PACKAGE (TOP VIEW)

				1
1DIR	1	\cup	48	10E
1B1 [2		47	1A1
1B2 [3		46	1A2
GND [4		45	GND
1B3 [5		44	1A3
1B4 [6		43] 1A4
v _{cc} [7		42] v _{cc}
1B5 🛚	8		41	1A5
1B6 🛚	9		40	1A6
GND [10			GND
1B7	11		38	1A7
1B8 🛚	12		37	1A8
2B1	13		36	2A1
2B2			35	2A2
GND [15		34] GND
2B3	16		33	
2B4	17		32	2A4
v_{cc}	18		31	
2B5 [30	
2B6			29	2A6
GND			28	GND
2B7			27	2A7
2B8 [23		26	2 <u>A8</u>
2DIR	24		25	20E

These devices can be used as two 8-bit transceivers or one 16-bit transceiver. They allow data transmission from the A bus to the B bus or from the B bus to the A bus, depending on the logic level at the direction-control (DIR) input. The output-enable (\overline{OE}) input can be used to disable the device so that the buses are effectively isolated.

When V_{CC} is between 0 and 2.1 V, the device is in the high-impedance state during power up or power down. However, to ensure the high-impedance state above 2.1 V, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN54ABT16245A is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74ABT16245A is characterized for operation from –40°C to 85°C.



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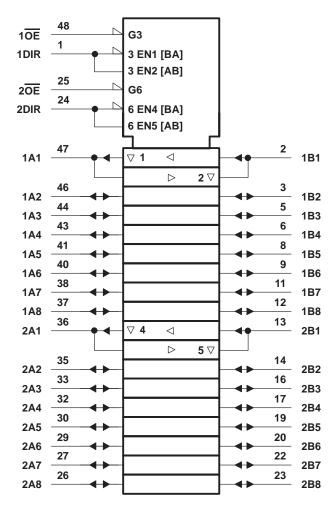


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FUNCTION TABLE (each 8-bit section)

INPUTS		ODEDATION
OE	DIR	OPERATION
L	L	B data to A bus
L	Н	A data to B bus
Н	Χ	Isolation

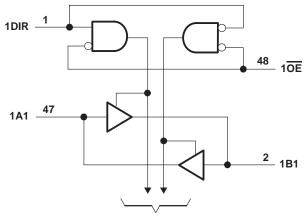
logic symbol†

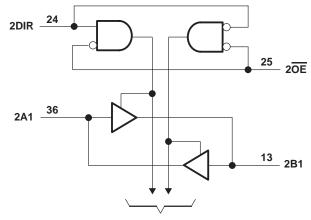


[†]This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



logic diagram (positive logic)





To Seven Other Channels To Seven Other Channels

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC} –0.5 V to 7 V
Input voltage range, V _I (except I/O ports) (see Note 1)
Voltage range applied to any output in the high or power-off state, VO
Current into any output in the low state, IO: SN54ABT16245A
SN74ABT16245A
Input clamp current, I_{IK} ($V_I < 0$)
Output clamp current, I_{OK} ($V_O < 0$)
Package thermal impedance, θ _{JA} (see Note 2): DGG package
DGV package 93°C/W
DL package 94°C/W
Storage temperature range, T _{stq} –65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

recommended operating conditions (see Note 3)

				16245A	SN74ABT	UNIT	
			MIN	MAX	MIN	MAX	UNII
V _{CC} Supply voltage		4.5	5.5	4.5	5.5	V	
VIH	High-level input voltage		2		2		V
V _{IL}	Low-level input voltage			0.8		0.8	V
VI	Input voltage		0	Vcc	0	Vcc	V
ІОН	OH High-level output current			-24		-32	mA
loL	Low-level output current			48		64	mA
Δt/Δν	Input transition rise or fall rate	Outputs enabled		10		10	ns/V
Δt/ΔV _{CC}	Power-up ramp rate		200		200		μs/V
TA	Operating free-air temperature		-55	125	-40	85	°C

NOTE 3: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



^{2.} The package thermal impedance is calculated in accordance with JESD 51.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		Т	A = 25°C	;	SN54ABT1	6245A	SN74ABT16245A		UNIT	
PAR	AMETER	TEST CONDITIONS		MIN	TYP [†]	MAX	MIN	MAX	MIN	MAX	UNII	
٧ıK		V _{CC} = 4.5 V,	I _I = -18 mA			-1.2		-1.2		-1.2	V	
		$V_{CC} = 4.5 \text{ V},$	$I_{OH} = -3 \text{ mA}$	2.5			2.5		2.5			
\/a		$V_{CC} = 5 V$,	$I_{OH} = -3 \text{ mA}$	3			3		3		V	
VOH	V 45V	$I_{OH} = -24 \text{ mA}$	2			2				V		
		V _{CC} = 4.5 V	$I_{OH} = -32 \text{ mA}$	2*					2			
VOL		V _{CC} = 4.5 V	I _{OL} = 48 mA			0.55		0.55			V	
VOL		VCC = 4.5 V	I _{OL} = 64 mA			0.55*				0.55	· ·	
V _{hys}					100						mV	
łı	Control inputs	$V_{CC} = 0 \text{ to } 5.5 \text{ V, V}$	I = VCC or GND			±1		±1		±1	μΑ	
'1	A or B ports $V_{CC} = 2.1 \text{ V to } 5.5 \text{ V},$ $V_{I} = V_{CC} \text{ or GND}$		V,			±20*		±100		±20	μΛ	
lozpu		$V_{CC} = 0 \text{ to } 2.1 \text{ V},$ $V_{O} = 0.5 \text{ V to } 2.7 \text{ V}, \overline{OE} = X$				±50**		±50**		±50	μΑ	
I _{OZPD}		$V_{CC} = 2.1 \text{ V to } 0,$ $V_{O} = 0.5 \text{ V to } 2.7 \text{ V}.$	OE = X			±50**		±50**		±50	μΑ	
lozH [‡]		$V_{CC} = 2.1 \text{ V to } 5.5$ $V_{O} = 2.7 \text{ V, } \overline{OE} \ge 2$	V, V			10§		10		10§	μΑ	
I _{OZL} ‡	$V_{CC} = 2.1 \text{ V to } 5.5 \text{ V},$ $V_{O} = 0.5 \text{ V}, \overline{OE} \ge 2 \text{ V}$		V, V			-10§		-10		-10§	μΑ	
l _{off}		$V_{CC} = 0$,	V_I or $V_O \le 4.5 \text{ V}$			±100				±100	μА	
ICEX		V _{CC} = 5.5 V, V _O = 5.5 V	Outputs high			50		50		50	μΑ	
IO¶		V _{CC} = 5.5 V,	V _O = 2.5 V	-50	-100	-180	-50	-180	-50	-180	mA	
	Vcc = 5.	V _{CC} = 5.5 V,	Outputs high			2		2		2		
ICC	A or B ports	$I_{O} = 0$,	Outputs low			32		32		32	mA	
		$V_I = V_{CC}$ or GND	Outputs disabled			2		2		2		
	Data innute	V _{CC} = 5.5 V, One input at 3.4 V,	Outputs enabled			2		1.5		2		
ΔI _{CC} #	Data Iliputs	Other inputs at VCC or GND	Outputs disabled			0.05		1		0.05	mA	
	Control inputs	V _{CC} = 5.5 V, One ir Other inputs at V _{CC}				1.5		1.5		1.5		
Ci	Control inputs	V _I = 2.5 V or 0.5 V		3						pF		
Со	A or B ports	V _O = 2.5 V or 0.5 V			6						pF	
	-	•					•		•			

^{*} On products compliant to MIL-PRF-38535, this parameter does not apply.



^{**} On products compliant to MIL-PRF-38535, this parameter is not production tested.

[†] All typical values are at V_{CC} = 5 V. ‡ The parameters I_{OZH} and I_{OZL} include the input leakage current.

[§] This limit may vary among suppliers.

[¶] Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

 $^{^{\#}}$ This is the increase in supply current for each input that is at the specified TTL voltage level rather than V $_{
m CC}$ or GND.

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switching characteristics over recommended ranges of supply voltage and operating free-air temperature, C_L = 50 pF (unless otherwise noted) (see Figure 1)

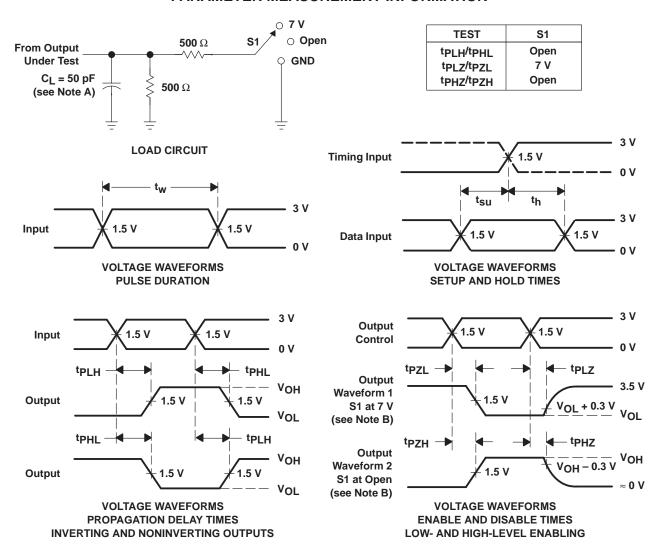
			SN54ABT16245A					
PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 5 V, T _A = 25°C			MIN	MAX	UNIT
			MIN	TYP	MAX			
t _{PLH}	A or B	B or A	0.5	2.2	3.4	0.5	4	ns
^t PHL		DOIA	0.5	2.3	3.8	0.5	4.6	115
^t PZH	ŌĒ	B or A	0.8	3.6	5.2	0.8	5.5	ns
t _{PZL}		BULK	0.9	3.7	6.1	0.1	7.3	115
^t PHZ	ŌĒ	B or A	1.3	4.4	5.8	1.3	6.3	ns
^t PLZ		BULK	1.4	3.3	4.7	1.4	5.3	115

switching characteristics over recommended ranges of supply voltage and operating free-air temperature, C_L = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _C	CC = 5 V 4 = 25°C	/, }	MIN	MAX	UNIT
			MIN	TYP	MAX			
t _{PLH}	A or B	B or A	1	2.2	3.4	1	3.9	ns
t _{PHL}		D OI A	1	2.3	3.7	1	4.2	115
^t PZH	OE	B or A	1	3.6	5.2	1	6.3	nc
t _{PZL}	OE OE	D OI A	1	3.7	5.4	1	6.4	ns
^t PHZ	OE	B or A	2	4.4	5.8	2	6.3	ns
tPLZ	OE	BUIA	1.5	3.3	4.7	1.5	5.2	115

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PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50~\Omega$, $t_f \leq$ 2.5 ns, $t_f \leq$ 2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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